

**Search Notes**

Application/Control No.

10/668,760

Examiner

Shih-wen Hsieh

Applicant(s)/Patent under  
Reexamination

MOTT ET AL.

Art Unit

2861

**SEARCHED**

Class	Subclass	Date	Examiner
347	22,24,29 30,32,33	10/4/2006	SWH

**INTERFERENCE SEARCHED**

Class	Subclass	Date	Examiner

**SEARCH NOTES  
(INCLUDING SEARCH STRATEGY)**

	DATE	EXMR